

# **Notice of References Cited**

Application/Control No.  
09/867,644

Applicant(s)/Patent Under  
Reexamination  
JUANG ET AL.

Examiner  
A. Sefer

Art Unit  
2826

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	B	US-20020075131	06-2002	Coates et al	338/308
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	U	Thomas et al. "Ti-Cu-Ni-Au (TCNA) compatibility with resistor and bilevel crossover circuit processing" (J. Vac. Sci. Technol., Vol. 13, No. 1, Jan/Feb. 1976).
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.